

**ABSTRACT**

A streak apparatus includes: a vacuum container 10 having an electron beam source 20 provided on one end side to emit an electron beam E and an output section 60 provided on the other end side to convert the electron beam into an image; an accelerating section 30 provided in the vacuum container to accelerate the electron beam; an irradiation optical system 40 for collecting and applying to-be-measured light R to the electron beam accelerated by the accelerating section; and a sweep section 50 provided between the accelerating section and the output section to sweep the electron beam having interacted with the to-be-measured light in a direction approximately perpendicular to the direction of a displacement of the electron beam generated through the interaction. This allows the streak apparatus to have a higher temporal resolution.